

_	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/706,902	CHAE ET AL.	
	Examiner	Art Unit	
	Binh X. Tran	1765	

SEARCHED					
Class	Subclass	Date	Examiner		
216	66	7/6/2006	вт		
216	72	7/6/2006	ВТ		
216	74	7/6/2006	ВТ		
438	725	7/6/2006	вт		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	1				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Updated search using USPAT, USPG- PUB, JPO, EPO, DERWENT databases	7/6/2006	ВТ		